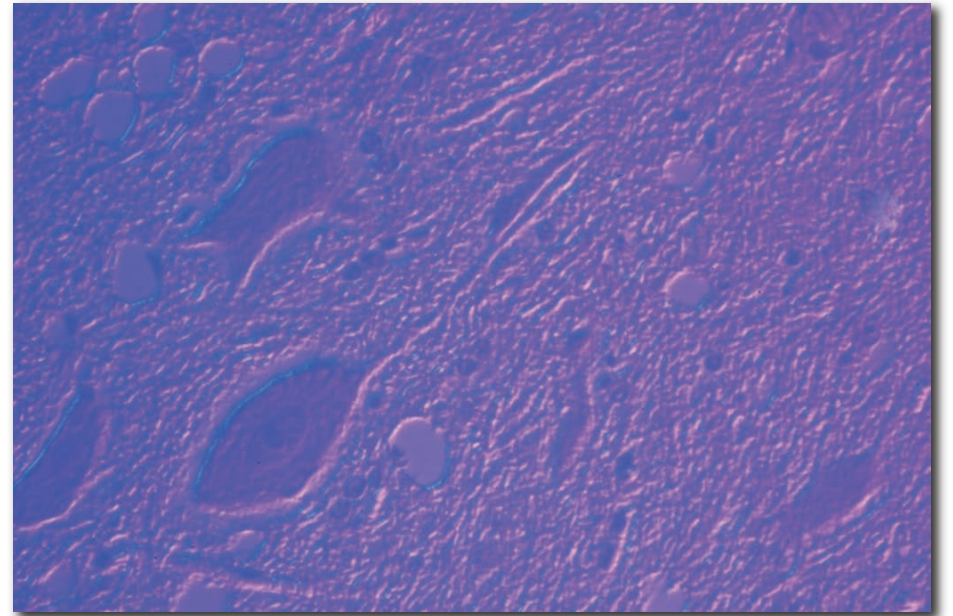
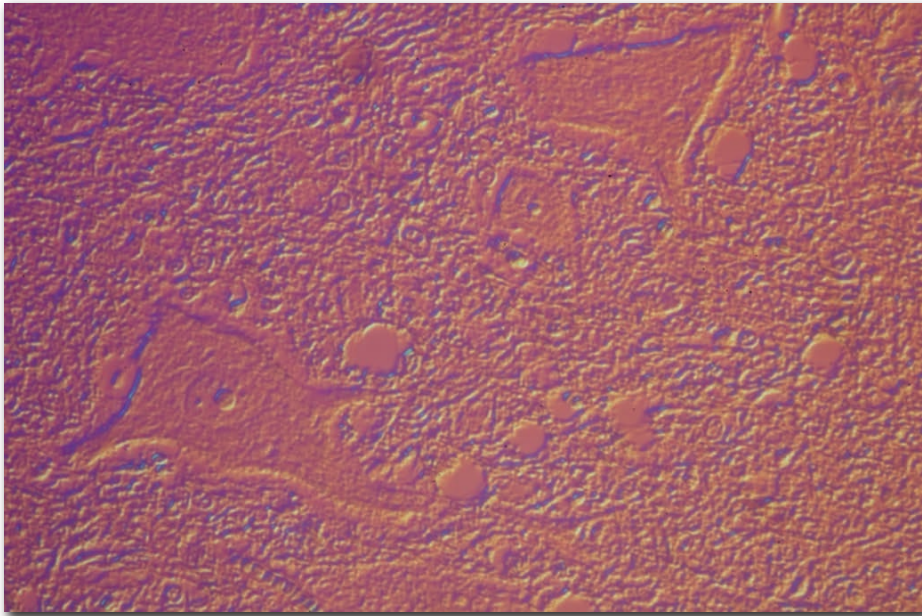
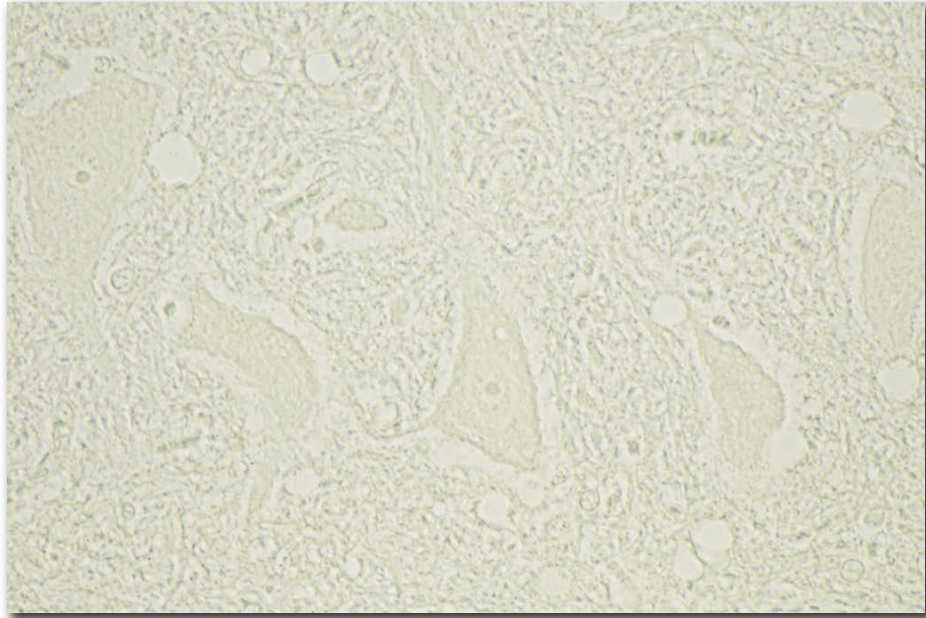


Differential Interference Contrast

DIC

Georges Nomarski - 1950



Interference image

Might use 2 Beam System or Quartz wedge

Reference beam

Sample beam

Special optics & filters

- Episcopic system
- Diascopic system

Requires polarized light

In front of sample - polarizer

After sample - Analyzer

Special Prism

Wollaston Prism - *a shearing prism* 2 quartz wedges

Different prism for each objective



Stress Free Objectives

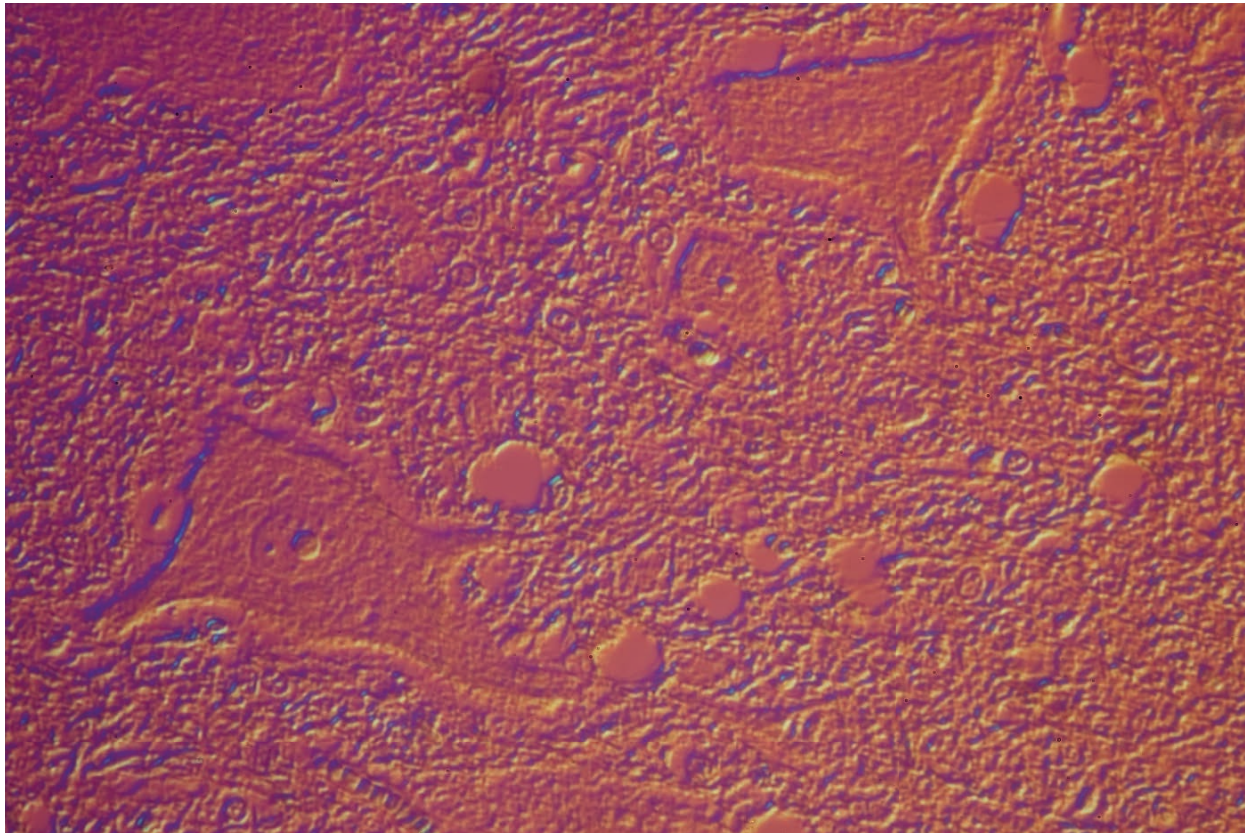
- DIC specific
- Special Annealing process

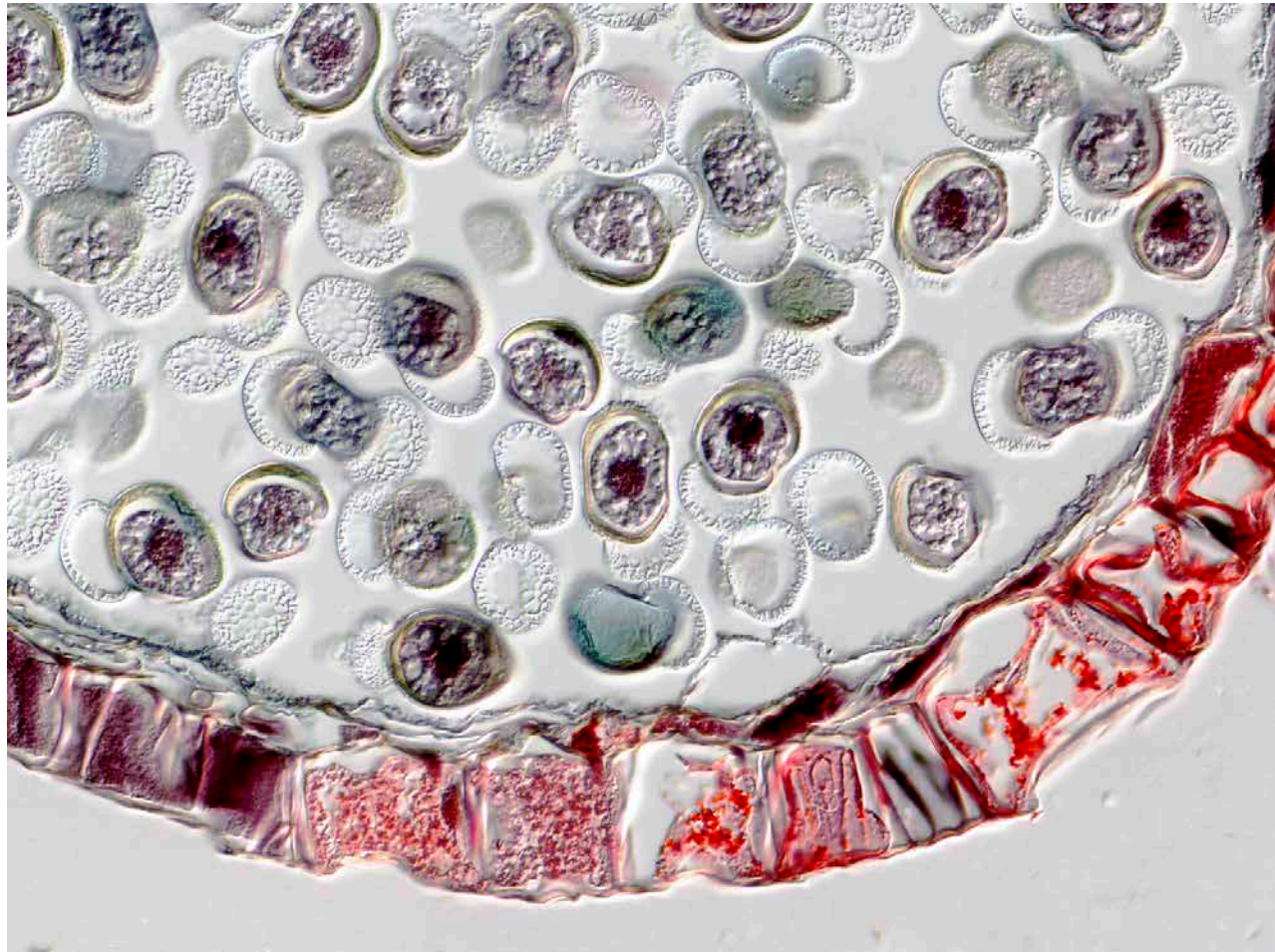
Interference image

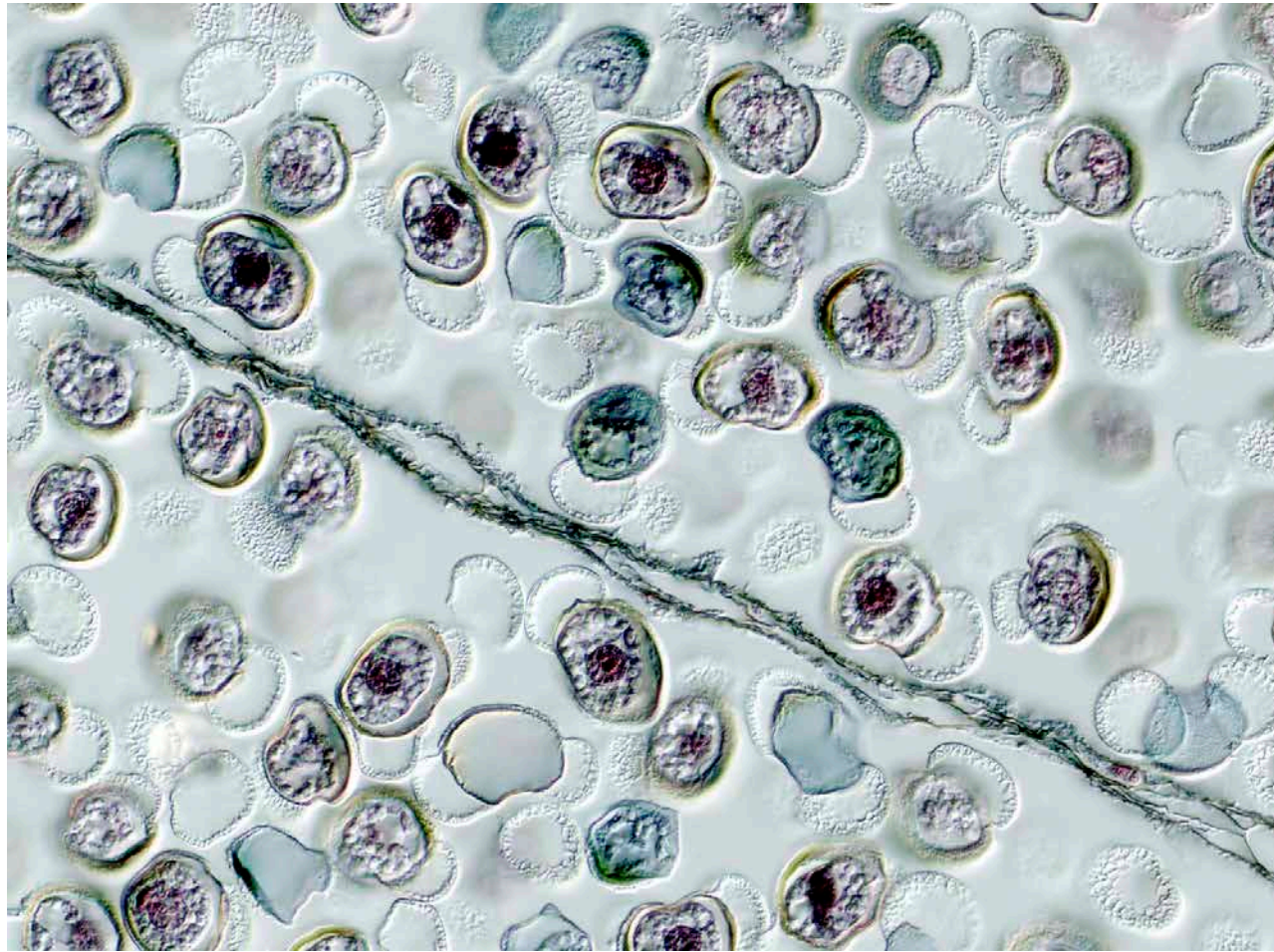
- Intermediate image plane
- Reference beam responsible, not sample

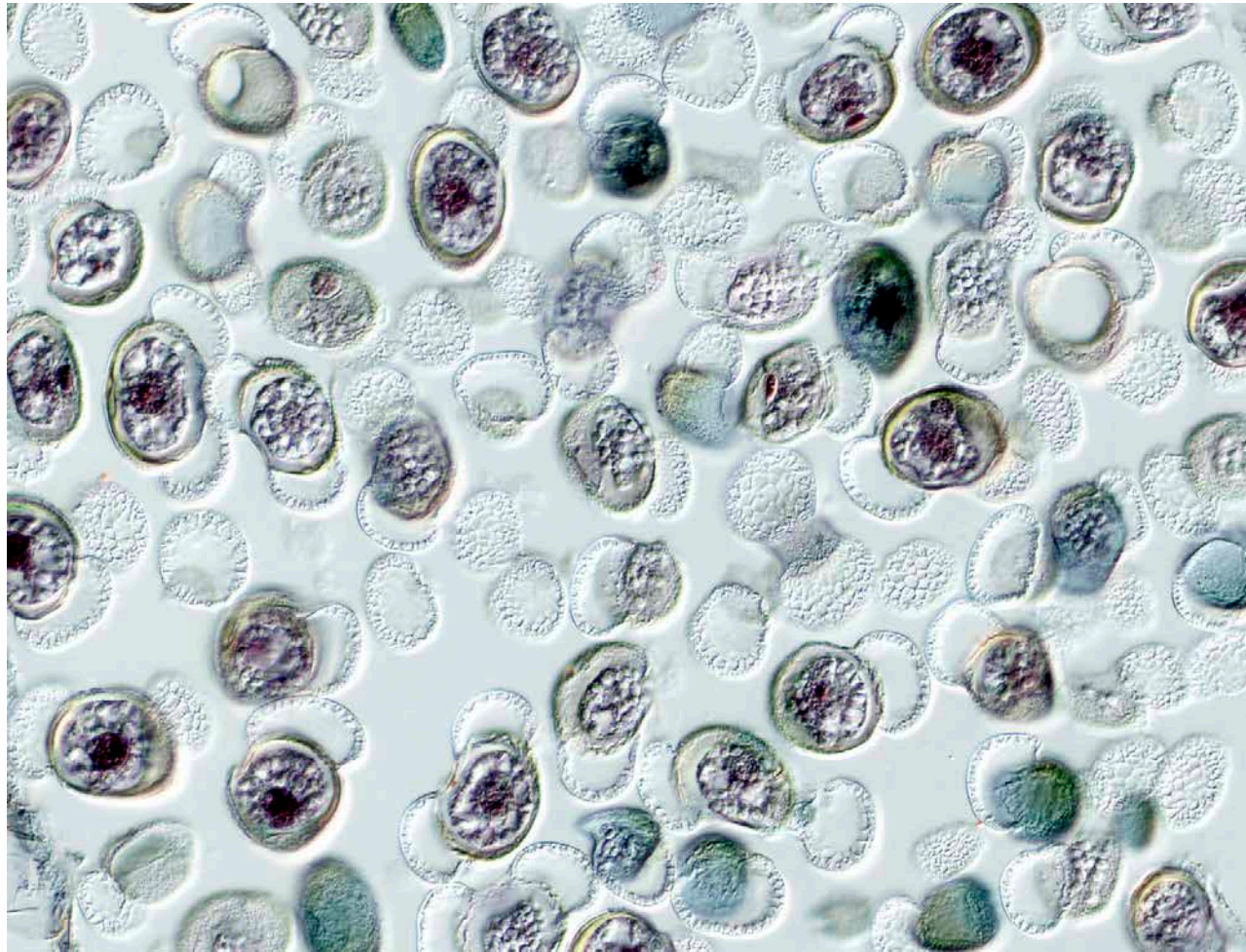
Images

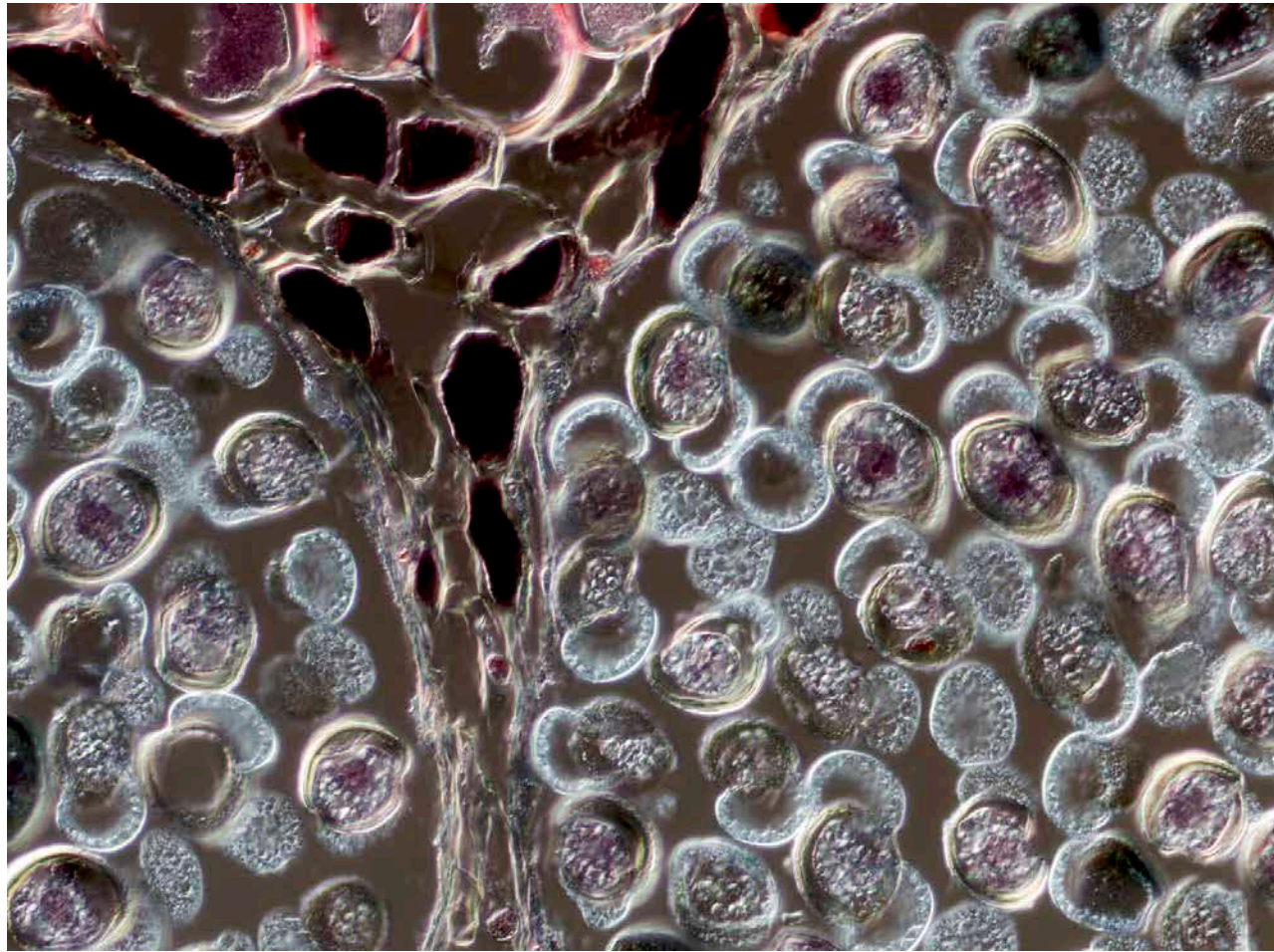
Pseudo-relief



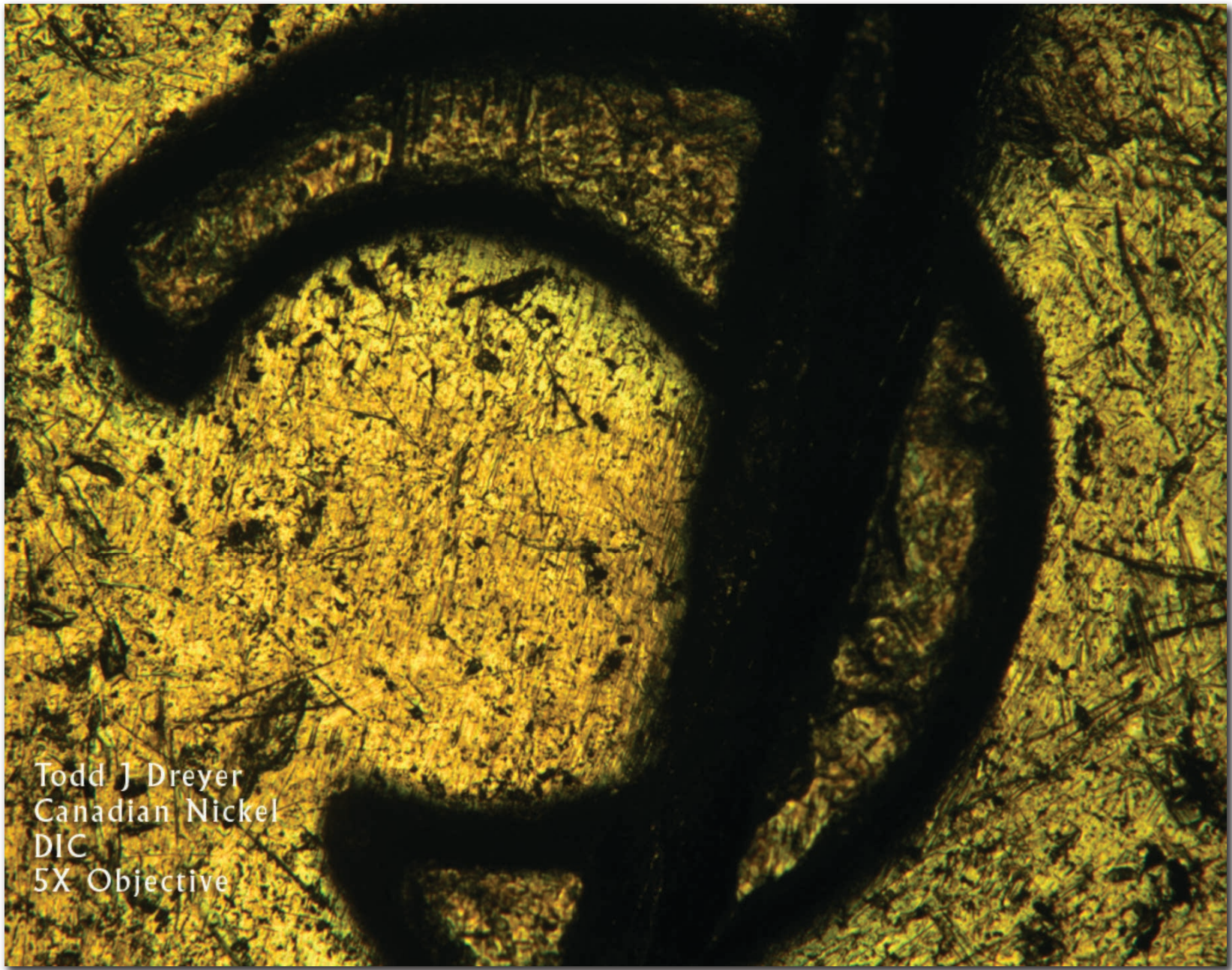






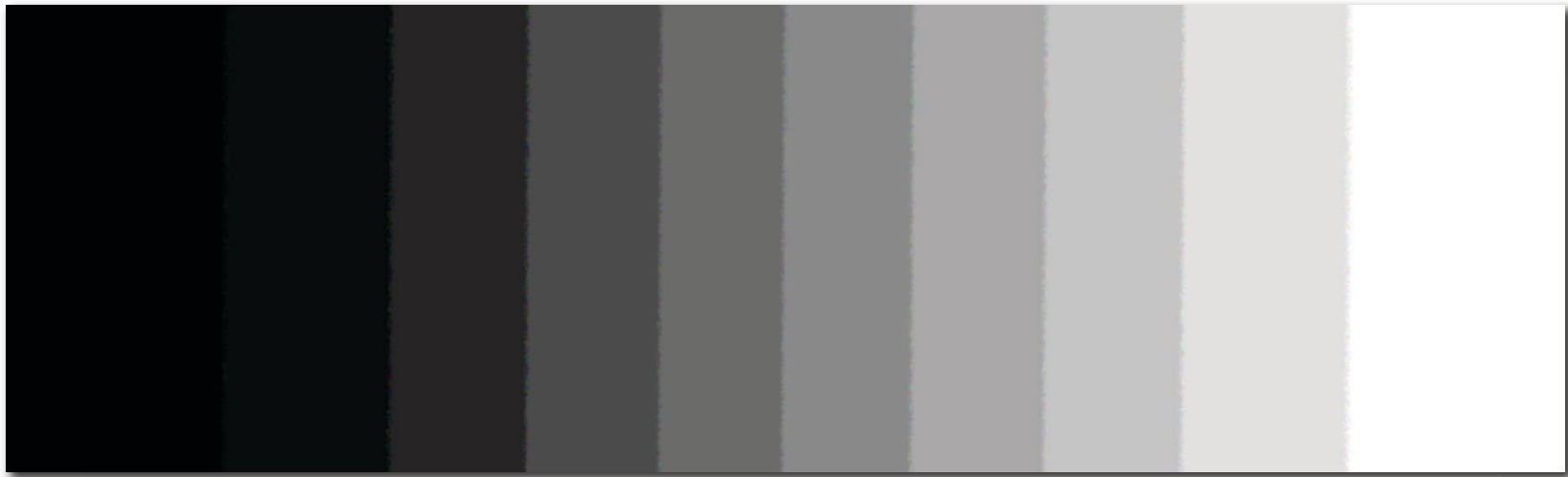






Todd J Dreyer
Canadian Nickel
DIC
5X Objective

Exposure Placement



BF

Reflected light

